Search	Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/644,937	LEE ET AL.	
Examiner	Art Unit	
William C. Doerrier	3744	

SEARCHED				
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INTERFERENCE SEARCHED				
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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EAST Stack See report	9-27-05	' (c (y		